

Notice of References Cited	Application/Control No. 10/724,133	Applicant(s)/Patent Under Reexamination LEE, JOON HYEON	
	Examiner DuyVu n. Deo	Art Unit 1765	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0173160	11-2002	Keil et al.	438/717
	B	US-6,063,695	05-2000	Lin et al.	438/462
	C	US-6,232,209	05-2001	Fujiwara et al.	438/585
	D	US-6,177,353	01-2001	Gutsche et al.	438/704
	E	US-6,117,345	09-2000	Liu et al.	216/19
	F	US-6,342,452	01-2002	Coronel et al.	438/710
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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